LIST	OF PRIOR	ART CIT	ED BY	ATTY. DOCKET NO. RPL-0010 REI		REISSUE APPLN. OF PATENT NO. 6,276,980B1		
APPLICANT				APPLICANT(S) Sang-Tae KIM				
(PTO-1449)				FILING DATE	GROUP 2879			
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W	5,998,920	12/1999	Kim					
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FOREIGN PATENT DOCUMENTS EXAMINER' Translation								
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OTHER	ART (Including	Author, Title.	Date, Pertiner	nt Pages, Publishe	r. Place	of Publication	n. Etc.	,
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EXAMINER DATE CONSIDERED 3/17/100								

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.